



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#10/ RCE
Advised
8/10/01

Applicant(s): Hsiao, Tommy C.; Hui, Angela T.; Ogle, Robert B.; Pham, Tuan Duc; Plat,
Marina V.; Ramsbey, Mark T.; Shen, Lewis

Assignee: Advanced Micro Devices, Inc.

Title: Polished Flash Process With Metal Gates And Improved Planarity

Serial No.: 09/430,366 Filing Date: October 28, 1999

Examiner: J. Chen Group Art Unit: 2813

Docket No.: M-7523 US

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COMMISSIONER FOR PATENTS
Washington, D. C. 20231

REQUEST FOR CONTINUED EXAMINATION (RCE)

Dear Sir:

This is a Request for Continued Examination (RCE) under 37 C.F.R. § 1.114 of the above-identified application.

Please consider the Response to Final Office Action dated April 6, 2001, which is being submitted for the Examiner's review with this request.

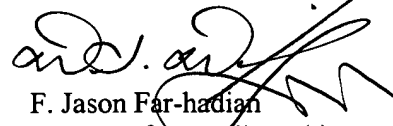
The RCE fee required under 37 C.F.R. § 1.17(e) is authorized in an accompanying transmittal letter.

Please contact the undersigned attorney at (949) 718-5200 with any questions concerning this request or the above-identified patent application.

EXPRESS MAIL LABEL NO:

EL849436115US

Respectfully submitted,


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Serial No. 09/430,366